MSEN5361 - Fundamentals of Surface and Thin Film Analysis

MSEN 5361 Fundamentals of Surface and Thin Film Analysis (3 semester credit hours) Survey of materials characterization techniques; Rutherford backscattering; secondary ion mass spectroscopy; ion channeling; scanning tunneling and transmission microscopy; x-ray photoelectron and Auger electron spectroscopy; x-ray and electron diffraction. Prerequisite: MSEN 5360 or equivalent. (3-0) R